

MT5060A

N-Channel Power[®] MOSFET

General Description

This N-Channel MOSFET is produced using MOS-TECH Semiconductor's advanced Power[®] process that has been especially tailored to minimize the on-state resistance. this device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.

Features

- $R_{DS(on)} = 11.2m\Omega @ V_{GS} = 10V, I_D = 12A$
- $R_{DS(on)} = 12.4m\Omega @ V_{GS} = 4.5V, I_D = 10A$
- High performance technology for extremely low $R_{DS(on)}$
- Termination is Lead-free and RoHS Compliant

Applications

- DC/DC buck converters
- Notebook battery management
- Load switching in notebook

Absolute Maximum Ratings ($T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Ratings	Units
V_{DS}	Drain to Source Voltage	60	V
V_{GS}	Gate to Source Voltage (Note 4)	± 25	V
I_D	Drain Current -Continuous (Package limited) $T_C = 25^\circ C$	20	A
	-Continuous (Silicon limited) $T_C = 25^\circ C$	50	
	-Continuous $T_A = 25^\circ C$ (Note 1a)	22	
	-Pulsed	90	
E_{AS}	Single Pulse Avalanche Energy (Note 3)	28	mJ
P_D	Power Dissipation $T_C = 25^\circ C$	26	W
	Power Dissipation $T_A = 25^\circ C$ (Note 1a)	2.6	
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to +150	$^\circ C$

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	5.0	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	53	

Package Marking and Ordering Information

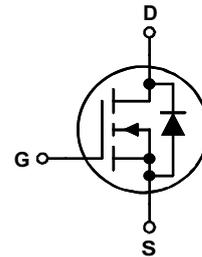
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
MT5060A	MT5060A	TO-251	-	-	50 units



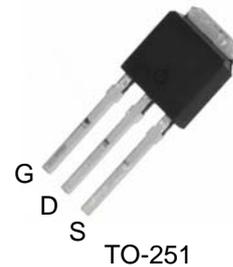
MT Semiconductor[®]

<http://www.mtsemi.com>

Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



Electrical Characteristics $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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Off Characteristics

BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250\text{ }\mu\text{A}$, $V_{GS} =$	60			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$, referenced to $25\text{ }^\circ\text{C}$		14		mV/ $^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24\text{ V}$, $V_{GS} = 0\text{ V}$			1	μA
I_{GSS}	Gate to Source Leakage Current, Forward	$V_{GS} = 20\text{ V}$, $V_{DS} = 0\text{ V}$			100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250\text{ }\mu\text{A}$	1.0		2.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$, referenced to $25\text{ }^\circ\text{C}$		-6		mV/ $^\circ\text{C}$
$r_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{ V}$, $I_D = 12\text{ A}$		11.2	12.5	m Ω
		$V_{GS} = 4.5\text{ V}$, $I_D = 10\text{ A}$		12.4	13.5	
		$V_{GS} = 10\text{ V}$, $I_D = 12\text{ A}$, $T_J = 125\text{ }^\circ\text{C}$		14.5	15.7	
g_{FS}	Forward Transconductance	$V_{DS} = 5\text{ V}$, $I_D = 12\text{ A}$		45		S

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 45\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1\text{ MHz}$		1011	1220	pF
C_{oss}	Output Capacitance			330	401	pF
C_{rss}	Reverse Transfer Capacitance			40	48	pF
R_g	Gate Resistance		0.2	1.0	2.0	Ω

Switching Characteristics

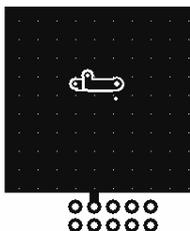
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 45\text{ V}$, $I_D = 12\text{ A}$, $V_{GS} = 10\text{ V}$, $R_{GEN} = 6\text{ }\Omega$		9	18	ns	
t_r	Rise Time			2	10	ns	
$t_{d(off)}$	Turn-Off Delay Time			15	31	ns	
t_f	Fall Time			2	10	ns	
Q_g	Total Gate Charge		$V_{GS} = 0\text{ V to }10\text{ V}$		16	26	nC
Q_g	Total Gate Charge	$V_{GS} = 0\text{ V to }5\text{ V}$	$V_{DD} = 15\text{ V}$, $I_D = 12\text{ A}$		8	11	nC
Q_{gs}	Gate to Source Charge				3.5		nC
Q_{gd}	Gate to Drain "Miller" Charge				1.9		nC

Drain-Source Diode Characteristics

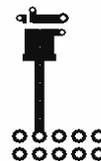
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0\text{ V}$, $I_S = 1.9\text{ A}$ (Note 2)		0.75	1.2	V
		$V_{GS} = 0\text{ V}$, $I_S = 12\text{ A}$ (Note 2)		0.80	1.2	
t_{rr}	Reverse Recovery Time	$I_F = 12\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$		26	41	ns
Q_{rr}	Reverse Recovery Charge			9	18	nC

Notes:

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in^2 pad 2 oz copper pad on a $1.5 \times 1.5\text{ in.}$ board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. $53\text{ }^\circ\text{C/W}$ when mounted on a 1 in^2 pad of 2 oz copper.



b. $125\text{ }^\circ\text{C/W}$ when mounted on a minimum pad of 2 oz copper.

2. Pulse Test: Pulse Width $< 300\text{ }\mu\text{s}$, Duty cycle $< 2.0\%$.

3. E_{AS} of 21 mJ is based on starting $T_J = 25\text{ }^\circ\text{C}$, $L = 0.3\text{ mH}$, $I_{AS} = 12\text{ A}$, $V_{DD} = 27\text{ V}$, $V_{GS} = 10\text{ V}$.

4. As an N-ch device, the negative V_{GS} rating is for low duty cycle pulse occurrence only. No continuous rating is implied.

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

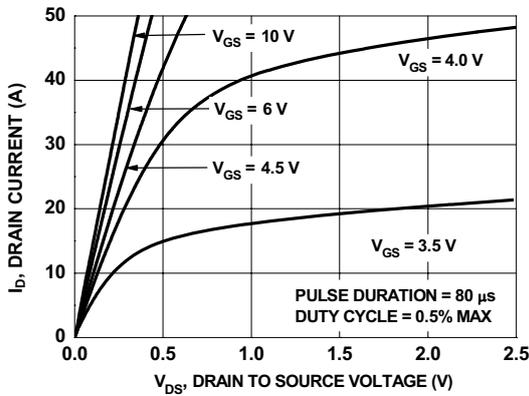


Figure 1. On Region Characteristics

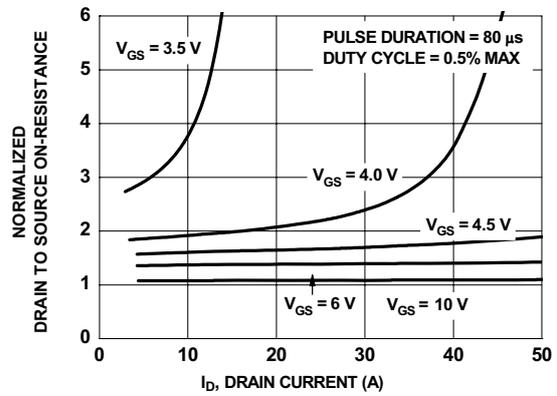


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

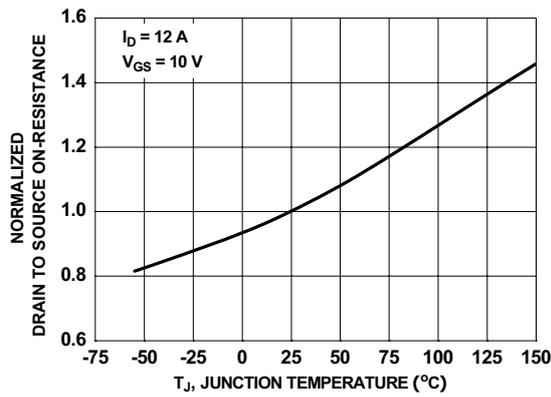


Figure 3. Normalized On Resistance vs Junction Temperature

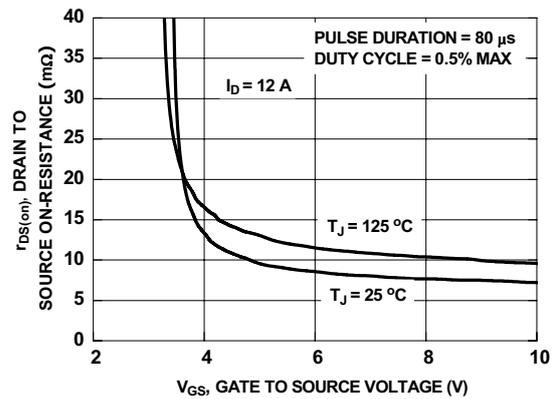


Figure 4. On-Resistance vs Gate to Source Voltage

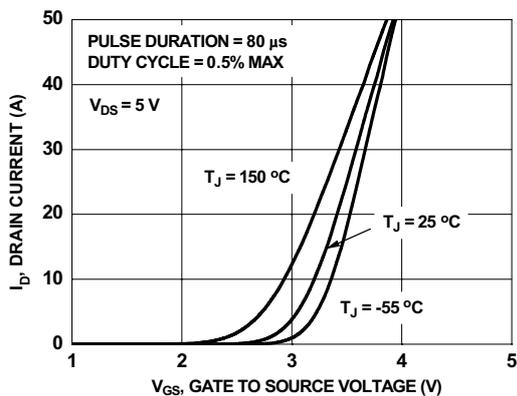


Figure 5. Transfer Characteristics

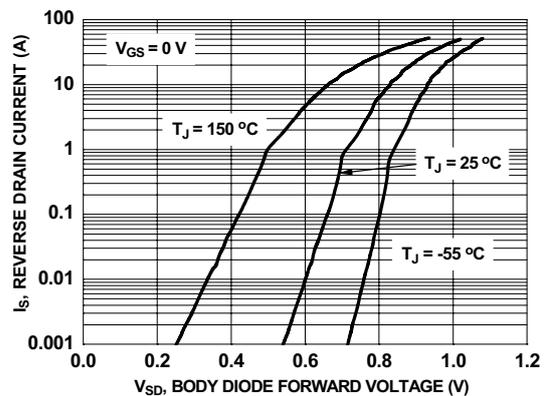


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted

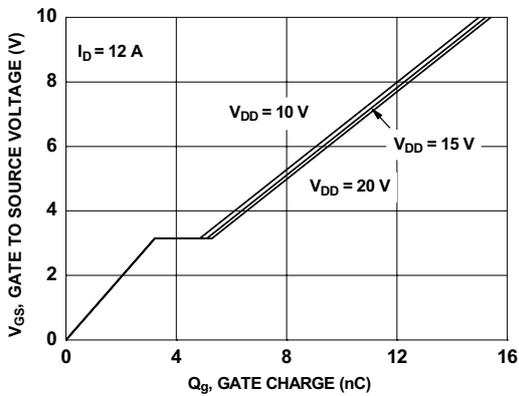


Figure 7. Gate Charge Characteristics

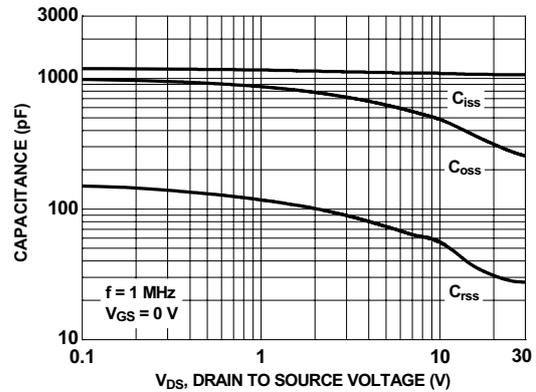


Figure 8. Capacitance vs Drain to Source Voltage

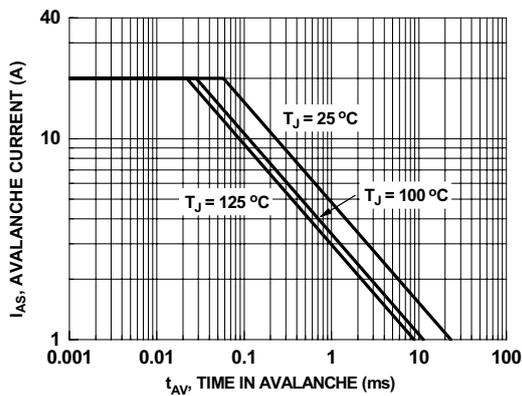


Figure 9. Unclamped Inductive Switching Capability

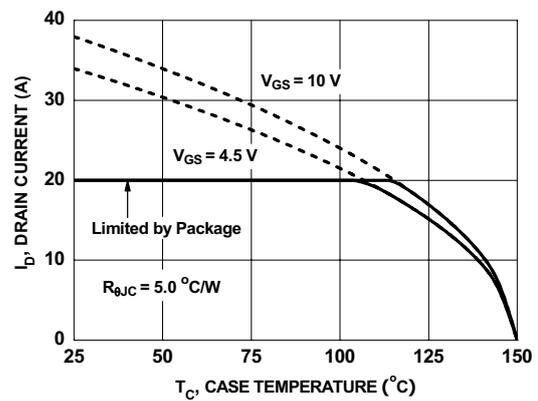


Figure 10. Maximum Continuous Drain Current vs Case Temperature

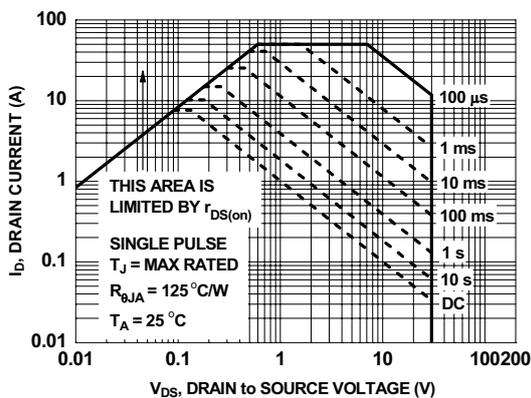


Figure 11. Forward Bias Safe Operating Area

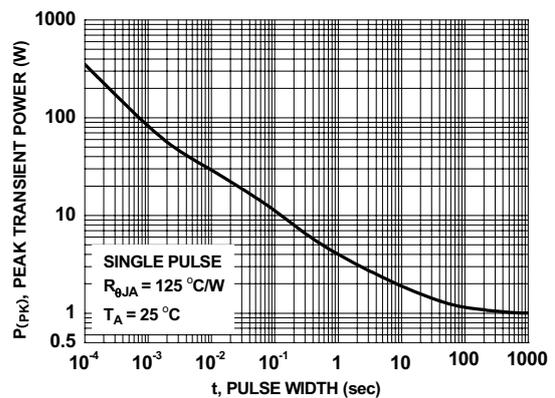


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted

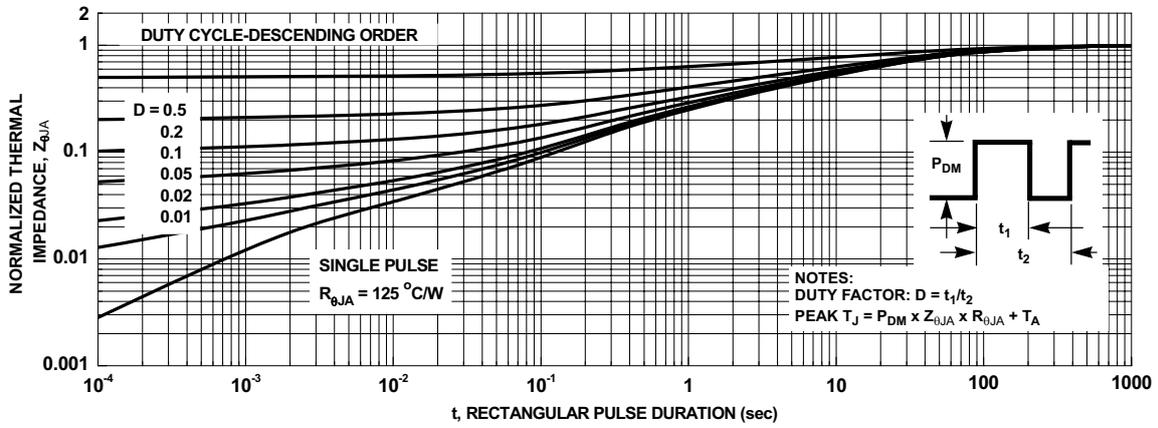
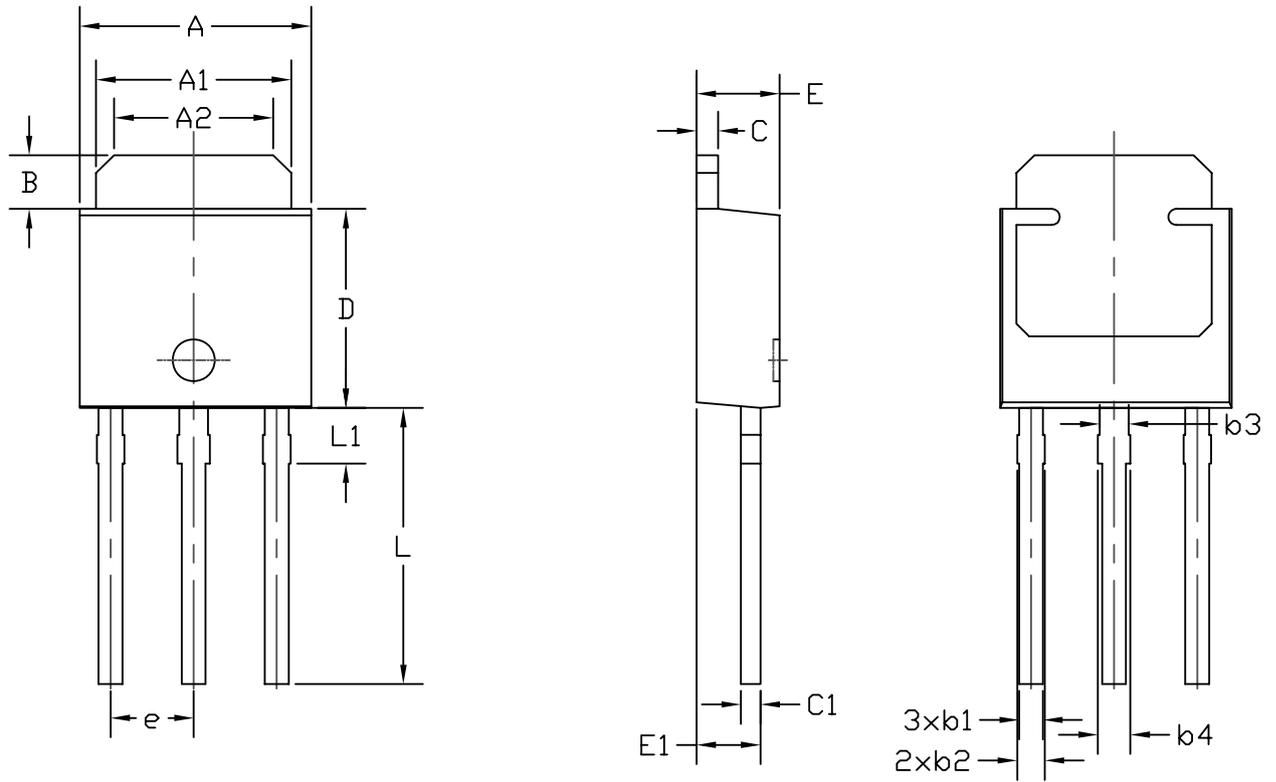


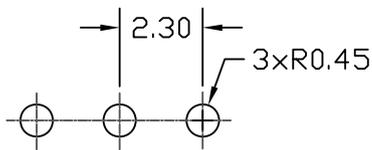
Figure 13. Junction-to-Ambient Transient Thermal Response Curve

Document No.	PO-00109
Version	B

TO251 PACKAGE OUTLINE



RECOMMENDED LAND PATTERN



UNIT:mm

SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	6.4	6.5	6.6	0.252	0.256	0.260
A1	5.3	5.4	5.5	0.209	0.213	0.217
A2	4.3	4.4	4.5	0.169	0.173	0.177
B	1.35	1.5	1.65	0.053	0.059	0.065
L1	1.55 REF			0.061 REF		
L	7.4	7.7	8	0.291	0.303	0.315
D	5.4	5.55	5.7	0.213	0.219	0.224
C	0.55	0.6	0.65	0.022	0.024	0.026
C1	0.49	0.54	0.59	0.019	0.021	0.023
E1	1.72	1.77	1.82	0.068	0.070	0.072
E	2.2	2.3	2.4	0.087	0.091	0.094
b1	0.6	---	0.75	0.024	---	0.030
b2	0.7	---	0.85	0.028	---	0.033
b3	0.8			0.031		
b4	0.9			0.035		
e	2.3			0.091		

NOTE

1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
MOLD FLASH SHOULD BE LESS THAN 6 MIL.
2. TOLERANCE 0.100 MILLIMETERS UNLESS OTHERWISE SPECIFIED.
3. CONTROLLING DIMENSION IS MILLIMETER.
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.
4. REFER TO JEDEC TO-251D AA.

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